# Photoconductivity in a-Si:H – a point of view

## 1. Introduction

In this work some experimental results concerning the photoconductivity of n-type a-Si:H layer samples obtained by glow discharge technics are presented. The lux-ampere characteristics are considered and plotted in a double-logarithmic scale. Their shapes may be approximated by some straight lines with variable slopes depending both on the temperature and the electric field in which the photo-carriers are generated. These experimental data are explained in the frame of a model including electron trapping and the recombination kinetics based on the energy band diagram with continuous distribution of gap states in semiconductors proposed initially by Rose [10] and extended by Wronski and Daniel [3] to the case of a-Si:H samples.

### 2. Fundamental notions

Briefly, the main theoretical models/notions used in this work, are:

- ✓ The conductivity in the presence of external photoexcitation is  $\sigma = \sigma_0 + \delta \sigma_{ph}$ , where  $\sigma_0 = e \mu n_0$  is the dark conductivity and  $\delta \sigma_{ph} = e \mu \delta n$  is the photoconductivity. (e is the electron charge,  $n_0$  the dark free electron concentration,  $\delta n$  the photoelectron concentration due to the light excitation, and  $\mu$  the electron mobility in the conduction band (extended states for electrons);
- ✓ The concentration of photogenerated electrons  $\delta n$  may be obtained by the well-known photoconduction law  $\delta n = G \tau_n (\delta n)$  with G = the volume photogeneration rate of free carriers and  $\tau_n(\delta n)$  = the electron lifetime (a function on the photoelectron concentration;
- ✓ the lifetime  $\tau_n$  is given by  $\tau_n = (v_T S_n p_r)^{-1}$  where  $v_T$  is the electron thermal velocity,  $S_n$ , the electron capture cross section, and  $p_r$  the density of electron recombination centres. The location of the recombination centres is defined by demarcation levels which are closely coupled to the quasi-Fermi levels.

After calculations showed in <u>https://doi.org/10.1002/pssb.2221790224</u> the photoconduction law becomes:

$$\delta n = \frac{\alpha G x}{T^{3/2}} \cdot \left(\frac{N_C}{n_0}\right)^x \cdot \left[\left(\frac{n}{n_0}\right)^x - 1\right]^{-1}$$

where  $x=T/T_C$ ,  $\alpha = (m/3k_B^3)^{1/2} \cdot (1/AS_n)$ ,  $n=n_0+\delta n$ , with all notations described in the published paper. This is a transcendental equation in  $\delta n$  which may be numerically solved.

The alternatives are to consider limit cases:

i) Low light intensity =>  $\delta n \sim G$ 

ii) High light intensity =>  $\delta n \sim G^{(1/(1+x))}$ 

iii) High light intensity and the concentration of the photogenerated carriers exceeds the density of recombination centers,  $p_r$ ,  $\delta n \sim G^{0.5}$ .

## 3. Experimental

#### 3.1 Sample preparation and measurements details

The n-type a-Si:H film samples have been deposited by rf discharge decomposition of SiH<sub>4</sub> (diluted 5% in argon) and PH<sub>3</sub>; the sample substrates were optical glass. The sample deposition: 600nm.

The electrical measurements have been made on ring-type configuration with the gap of the coplanar AI electrodes of about 70  $\mu$ m. All the measurements have been carried out in the temperature range 290 to 360 K, in a vacuum cryostat ( $\approx 10^{-2}$ Pa) having a thermocouple in good contact with the sample. Electrical fields corresponding to voltage in the range 0.5 V to 18 V have been applied between the two electrodes to drive the photogenerated carriers. The dark current-voltage characteristic exhibited ohmic behavior.

The photoconductivity has been measured on known and reproducible states of electrical conductivity for various values of the light intensity ranging from  $10^{12}$  to  $10^{15}$  photons cm<sup>-2</sup> s<sup>-1</sup>. The measured photocurrent values have been significantly greater than the dark current values and the photocarrier generation may be considered as uniform [11].

#### 3.2 Results

The lux-ampere characteristics are plotted in double logarithmic scale,  $Ig I_{ph} = f(Ig \phi)$ , where  $I_{ph}$  is the photocurrent and  $\phi$  is the light flux (ranged

between  $10^{13}$  and  $10^{15}$  cm<sup>-2</sup> s<sup>-1</sup>). In Fig. 1 these characteristics are plotted for various driving electric fields between the electrodes at a temperature *T* = 290 K and in Fig. 2 the same dependence is plotted for various ambient temperatures at a driving electric field E = 1.43 x 104 V/m.



v 2.26x10<sup>4</sup>, + 3.68 x10<sup>4</sup> V/m

305K, v 320K, ◊ 340K, □ 360K

The experimental data may be approximated by two straight lines with distinct slopes. This behavior agrees with that mentioned in [3, 4].

The first group of straight lines has slope values (the parameter  $\gamma$ ) between 0.75 and 0.87, while the second group of straight lines reveals  $\gamma$  in the range 0.50 to 0.54.

Therefore, the behavior of the dependence  $\lg I_{ph} = \gamma \lg \Phi$  agrees with that described in cases (ii) and (iii) for high light intensity. The second group of straight lines may be taken with enough accuracy as case (iii) considering approximatively  $\gamma = 0.5$ . Both interpretations, based on the bimolecular recombination model [1], explain satisfactorily the dependence  $I_{ph} \sim \Phi^{0.5}$ .

Because of this in the following we shall analyze the first group of straight lines characterized by a variable parameter  $\gamma$  in the range 0.5 to 1 presenting a significant departure from the case described commonly by bimolecular recombination. One may observe that the variable  $x = T/T_0$ . satisfies the transcendental equation

$$Lg \ x = x \cdot Lg\left(\frac{\delta n}{N_c}\right) + Lg\left(\frac{\delta n \cdot T^{3/2}}{\alpha \cdot G}\right)$$

which has been solved graphically.

A special attention was paid to the dependency of the  $\gamma$  parameter versus the electrical field and the measurement temperature. This is suggestively presented in *Figure 3* and *Figure 4*.



Figure 4. The  $\gamma$  parameter versus the electric field for T=290K



Figure 3. The dependence of the  $\gamma$  parameter on temperature for electrical field of 1.43 10<sup>4</sup> V/m